IFW

TRE											
TRANSMITTA	Docket No.										
NOV 1 2 2004	(Under 37 CFF	BUR920040134US1									
Re Application	Faul H. Bergero	n et al.									
Tauri. Bergeron et al.											
Application No.	Filing Date	Examiner	Customer No.	Group Art Unit	Confirmation No.						
10/711,978	10/18/2004	Unassigned	044152	Unassigned Unassigned							
Title: IMPROVING SYSTEMATIC YIELD IN SEMICONDUCTOR MANUFACTURE											
		Address to:									
		Commissioner for Paten	ts								
		P.O. Box 1450 Alexandria, VA 22313-14	50								
		37 CFR 1.97(b)									
1. 🗵 The Inform	nation Disclosure Sta	tement submitted herewith is b	eing filed within	n three months	of the filing						
	•	than a continued prosecution	• •		• •						
		try of the national stage as set of a first Office Action on the m									
		est for continued examination un		-	mst Onice						
	3										
		37 CFR 1.97(c)									
_		• • • • • • • • • • • • • • • • • • • •									
		atement submitted herewith is I									
CFR 1.97(b), provided that the Information Disclosure Statement is filed before the mailing date of a Final Action under 37 CFR 1.113, a Notice of Allowance under 37 CFR 1.311, or an Action that											
		the application, and is accomp									
		- 27 OFD 4 07/-\:									
□ tne s	statement specified i	. ,			,						
		OR									
☐ the	fee set forth in 37 CF	FR 1.17(p).									

NSMITTAL OF INFORMATION DISCLOSURE STATEMENT Docket No. (Under 37 CFR 1.97(b) or 1.97(c)) BUR920040134US1 ation: Paul H. Bergeron et al. Customer No. Group Art Unit Confirmation No. Filing Date Examiner Application No. Unassigned 044152 Unassigned 10/711,978 10/18/2004 Unassigned Title: IMPROVING SYSTEMATIC YIELD IN SEMICONDUCTOR MANUFACTURE Payment of Fee (Only complete if Applicant elects to pay the fee set forth in 37 CFR 1.17(p)) A check in the amount of is attached. ☑ The Director is hereby authorized to charge and credit Deposit Account No. 09-0456 as described below. Charge the amount of Credit any overpayment. X Charge any additional fee required. Payment by credit card. Form PTO-2038 is attached. WARNING: Information on this form may become public. Credit card information should not be included on this form. Provide credit card information and authorization on PTO-2038. Certificate of Transmission by Facsimile* Certificate of Mailing by First Class Mail I hereby certify that this correspondence is being deposited I certify that this document and authorization to charge deposit with the United States Postal Service with sufficient postage account is being facsimile transmitted to the United States as first class mail in an envelope addressed to Patent and Trademark Office (Fax. No. "Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450" [37 CFR 1.8(a)] on (Date) (Date) Signature of Person Mailing Correspondence Signature MUELL Typed or Printed Name of Person Signing Certificate Typed or Printed Name of Person Mailing Certificate *This certificate may only be used if paying by deposit account. Dated: 11/10/04 Signature Richard M. Kotulak, Reg. 27712 IP Law Dept., 972E **IBM Corporation** 1000 River Street Essex Junction, VT 05452 Telephone: 802-759-4457

CC:

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

n re patent application of Paul H. Bergeron, et al. Dodge No.: BUR920040134US1

Serial No.: Unassigned 10/7/1, 978

Group Art Unit: Unassigned

Filed: Concurrently 10/18/2004

Examiner: Unassigned

For: IM

IMPROVING SYSTEMATIC YIELD IN SEMICORDUCTOR MANUFACTURE

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

Under the provisions of 37 CFR §1.97 through §1.99 and pursuant to applicant's duty of disclosure under 37 CFR §1.56, applicant respectfully brings the following documents, listed on the attached form PTO-1449, to the attention of the Examiner in charge of the above-identified application. A copy of the non-US patent documents is enclosed for the convenience of the Examiner.

This citation does not constitute an admission that the references are relevant or material to the claims. They are only cited as constituting related art of which the applicant is aware.

It is respectfully requested that the listed references be considered by the Examiner and formally made of record in this application.

Respectfully submitted,

Andrew M. Calder w Reg. No. 38,093

McGuireWoods LLP 1750 Tysons Boulevard, Suite 1800 McLean, VA 22102 (703)712-5000

\\COM\451537.1

Form PTO-1449 (Modified) .	Attorney Docket No.:	Serial No:	
. 66	BUR920040134US!	Unassigned	
LIST OF PATENTS AND PUBLICANT'S	Applicant:		
INFORMATION DISCLOSURE STATEMENT	Paul H. Bergeron, et al.		
(Use several sheets if necessary) NOV 1 2 2004 Page I of I	Filing Date:	Group:	
(SSS SST AND A SS S	Concurrently	Unassigned	
THE PROPERTY OF			

		FOREIGN PATEN	I DOCUMENTS									
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO						
OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)												
	R.L. Hunt, et al., "Automatically Rerouting Wires on Printed-Circuit Boards to Avoid Noise Coupling Problems", IBM Technical Disclosure Bulletin, Vol. 18, No. 3, August 1975, p. 762-766.											
	Computer Aided D	J.Z. Su, et al., "Post-Route Optimization for Improved Yield Using a Rubber-Band Wiring Model", Computer Aided Design, 1997. Digest of Technical Papers., 1997. IEEE/ACM International Conference on Nov. 9-13, 1997, p. 700-706.										
	1 1 ' '	R. Prasad, et al., "The Effect of Placement on Yield for Standard Cell Designs", url = "citeseer.ist.psu.edu/380923.html"										
	, ,	A.B. Kahng, et al., "Non-Tree Routing for Reliability and Yield Improvement", Computer Aided Design, 2002. ICCAD 2002. IEEE/ACM International Conference on Nov. 10-14, 2002, p. 260-266.										
	A. Venkataraman, et al., "Determination of Yield Bounds Prior to Routing", Defect and Fault Tolerance in VLSI Systems, 1999. DFT '99. International Symposium on Nov. 1999, p. 4-13.											
	P. Kudva, et al., "N	P. Kudva, et al., "Measurements for Structural Logic Synthesis", Computer Aided Design of Integrated Circuits and Systems, IEEE Transactions on Vol. 22, Iss. 6, June 2003, p. 665-674.										
EXAMINER			DATE CONSIDERE	D								

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not conformance and not considered. Include copy of this form with next communication to

applicant.